Amendment to the Abstract:

Please replace the abstract with the rewritten abstract provided on a separate sheet attached hereto.

Attachment: Replacement Sheet for Abstract

REPLACEMENT SHEET FOR ABSTRACT

A method of manufacturing a semiconductor device may include forming a fin structure on an insulator and forming a gate structure over a channel portion of the fin structure. The method may also include forming a sacrificial oxide dielectric layer around adjacent the gate structure and removing etching the gate structure to define a gate recess within the sacrificial oxide layer. A metal gate may be formed in the gate recess[[,]] and the sacrificial oxide layer may be removed.